

MOTOROLA
SEMICONDUCTOR
TECHNICAL DATA

T-33-07

MPS-U05
MPS-U06

**NOT RECOMMENDED
FOR NEW DESIGNS**

**NPN SILICON ANNULAR
AMPLIFIER TRANSISTORS**

... designed for general-purpose, high-voltage amplifier and driver applications.

- High Collector-Emitter Breakdown Voltage –
V_{(BR)CEO} = 60 Vdc (Min) @ I_C = 1.0 mA_{dc} — MPS-U05
80 Vdc (Min) @ I_C = 1.0 mA_{dc} — MPS-U06
- High Power Dissipation – P_D = 10 W @ T_C = 25°C
- Complements to PNP MPS-U55 and MPS-U56

**NPN SILICON
AMPLIFIER TRANSISTORS**

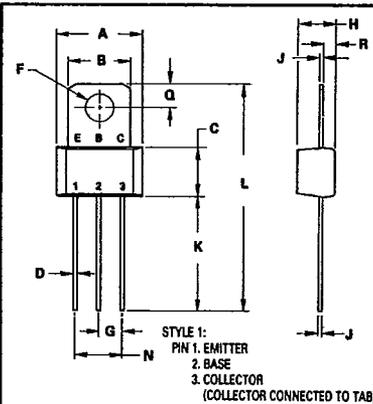


MAXIMUM RATINGS

Rating	Symbol	MPS-U05	MPS-U06	Unit
Collector-Emitter Voltage	V _{CEO}	60	80	Vdc
Collector-Base Voltage	V _{CB}	60	80	Vdc
Emitter-Base Voltage	V _{EB}	4.0		Vdc
Collector Current – Continuous	I _C	2.0		Adc
Total Power Dissipation @ T _A = 25°C	P _D	1.0		Watt
Derate above 25°C		8.0		mW/°C
Total Power Dissipation @ T _C = 25°C	P _D	10		Watts
Derate above 25°C		80		mW/°C
Operating and Storage Junction Temperature Range	T _J , T _{stg}	-55 to +150		°C

THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Case	R _{θJC}	12.5	°C/W
Thermal Resistance, Junction to Ambient	R _{θJA}	125	°C/W



NOTE:
1. LEADS WITHIN 0.15 mm(0.006) TOTAL OF TRUE POSITION AT CASE, AT MAXIMUM MATERIAL CONDITION.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	9.14	9.53	0.360	0.375
B	6.60	7.24	0.260	0.286
C	5.41	5.66	0.213	0.223
D	0.38	0.53	0.015	0.021
F	3.18	3.33	0.125	0.131
G	2.54 BSC		0.100 BSC	
H	3.94	4.19	0.155	0.165
J	0.36	0.41	0.014	0.016
K	11.63	12.70	0.458	0.500
L	24.58	25.53	0.968	1.005
M	5.08 BSC		0.200 BSC	
Q	2.39	2.69	0.094	0.106
R	1.14	1.40	0.045	0.055

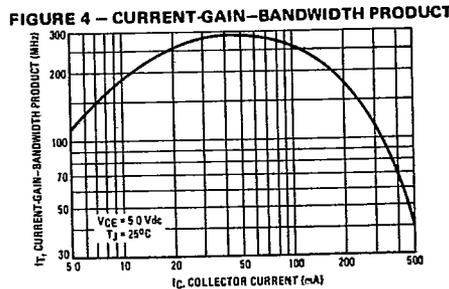
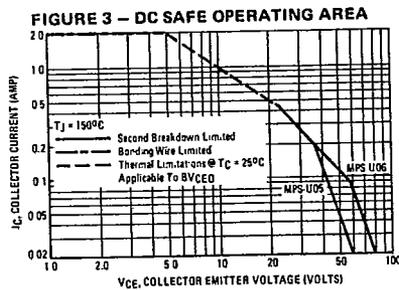
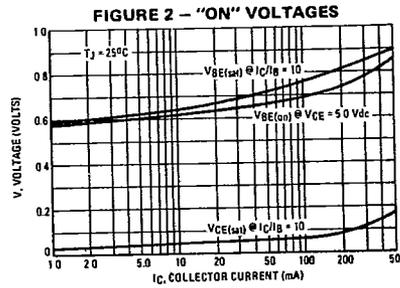
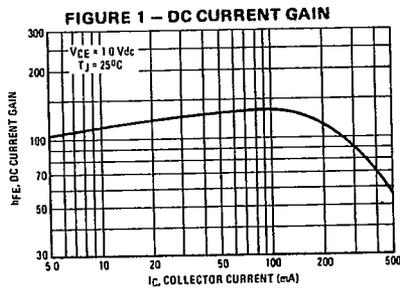
CASE 152-02

T-33-07

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS					
Collector-Emitter Breakdown Voltage ($I_C = 1.0 \text{ mA}$, $I_B = 0$)	$V_{(BR)CEO}$	60 80	— —	— —	Vdc
Emitter-Base Breakdown Voltage ($I_E = 100 \mu\text{A}$, $I_C = 0$)	$V_{(BR)EBO}$	4.0	—	—	Vdc
Collector Cutoff Current ($V_{CB} = 40 \text{ Vdc}$, $I_E = 0$) ($V_{CB} = 60 \text{ Vdc}$, $I_E = 0$)	I_{CBO}	— —	— —	100 100	nAdc
ON CHARACTERISTICS					
DC Current Gain (1) ($I_C = 50 \text{ mA}$, $V_{CE} = 1.0 \text{ Vdc}$) ($I_C = 250 \text{ mA}$, $V_{CE} = 1.0 \text{ Vdc}$) ($I_C = 500 \text{ mA}$, $V_{CE} = 1.0 \text{ Vdc}$)	h_{FE}	80 60 —	125 100 55	— — —	—
Collector-Emitter Saturation Voltage(1) ($I_C = 250 \text{ mA}$, $I_B = 10 \text{ mA}$) ($I_C = 250 \text{ mA}$, $I_B = 25 \text{ mA}$)	$V_{CE(sat)}$	— —	0.18 0.1	0.4 —	Vdc
Base-Emitter On Voltage (1) ($I_C = 250 \text{ mA}$, $V_{CE} = 5.0 \text{ Vdc}$)	$V_{BE(on)}$	—	0.74	1.2	Vdc
SMALL-SIGNAL CHARACTERISTICS					
Current-Gain-Bandwidth Product (1) ($I_C = 250 \text{ mA}$, $V_{CE} = 5.0 \text{ Vdc}$, $f = 100 \text{ MHz}$)	f_T	50	150	—	MHz
Output Capacitance ($V_{CB} = 10 \text{ Vdc}$, $I_E = 0$, $f = 100 \text{ kHz}$)	C_{ob}	—	6.0	12	pF

(1) Pulse Test: Pulse Width $\leq 300 \mu\text{s}$, Duty Cycle $\leq 2.0\%$.



There are two limitations on the power handling ability of a transistor: junction temperature and second breakdown. Safe operating area curves indicate $I_C - V_{CE}$ limits of the transistor that must be observed for reliable operation; i.e., the transistor must not be subjected to greater dissipation than the curves indicate.

The data of Figure 3 is based on $T_{J(pk)} = 150^\circ\text{C}$; T_C is variable depending on conditions. At high case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by second breakdown.

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